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Details

Product Status	Active
Number of LABs/CLBs	5820
Number of Logic Elements/Cells	74496
Total RAM Bits	5750784
Number of I/O	360
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	784-BBGA, FCBGA
Supplier Device Package	784-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vlx75t-3ffg784c

Table 4: **Typical Quiescent Supply Current** *(Cont'd)*

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M)[2]	-1L (C)	-1L (I)[1]	
I_{CCAUXQ}	Quiescent V_{CCAUX} supply current	XC6VLX75T	45	45	45	N/A	45	45	mA
		XC6VLX130T	75	75	75	N/A	75	75	mA
		XC6VLX195T	113	113	113	N/A	113	113	mA
		XC6VLX240T	135	135	135	N/A	135	135	mA
		XC6VLX365T	191	191	191	N/A	191	191	mA
		XC6VLX550T[3]	N/A	286	286	N/A	286	286	mA
		XC6VLX760T[3]	N/A	387	387	N/A	387	387	mA
		XC6VSX315T	186	186	186	N/A	186	186	mA
		XC6VSX475T[3]	N/A	279	279	N/A	279	279	mA
		XC6VHX250T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX255T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX380T[4]	227	227	227	N/A	N/A	N/A	mA
		XC6VHX565T[5]	N/A	315	315	N/A	N/A	N/A	mA
		XQ6VLX130T[6]	N/A	75	N/A	75	N/A	75	mA
		XQ6VLX240T[6]	N/A	135	N/A	135	N/A	135	mA
		XQ6VLX550T[7]	N/A	N/A	N/A	286	N/A	286	mA
		XQ6VSX315T[6]	N/A	186	N/A	186	N/A	186	mA
		XQ6VSX475T[7]	N/A	N/A	N/A	279	N/A	279	mA

Notes:

1. Typical values are specified at nominal voltage, 85°C junction temperatures (T_j). -1 and -2 industrial (I) grade devices have the same typical values as commercial (C) grade devices at 85°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. -1L industrial temperature range devices have the values specified in this column.
2. Use the XPE tool to calculate 125°C values for -1M temperature range devices.
3. The -2E extended temperature range (T_j = 0°C to +100°C) is only available in these devices. The -2I temperature range (T_j = –40°C to +100°C) is available for all other devices except the XC6VHX565T.
4. The XC6VHX380T is available with both -2E and -2I temperature ranges.
5. The XC6VHX565T is only available in the following temperature ranges: -1C, -1I, -2C, and -2E.
6. The XQ6VLX130T, XQ6VLX240T, and XQ6VSX315T are available in -2I, -1I, -1M, and -1LI temperature ranges.
7. The XQ6VLX550T and the XQ6VSX475T are only available in -1I and -1LI temperature ranges.
8. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
9. If DCI or differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPE or XPower Analyzer (XPA) tools.

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Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on sequence and ramp rate of the power supply.

The recommended power-on sequence for Virtex-6 devices is V_{CCINT}, V_{CCAUX}, and V_{CCO} to meet the power-up current requirements listed in Table 5. V_{CCINT} can be powered up or down at any time, but power up current specifications can vary from Table 5. The device will have no physical damage or reliability concerns if V_{CCINT}, V_{CCAUX}, and V_{CCO} sequence cannot be followed.

If the recommended power-up sequence cannot be followed and the I/Os must remain 3-stated throughout configuration, then V_{CCAUX} must be powered prior to V_{CCO} or V_{CCAUX} and V_{CCO} must be powered by the same supply. Similarly, for power-down, the reverse V_{CCAUX} and V_{CCO} sequence is recommended if the I/Os are to remain 3-stated.

The GTH transceiver supplies must be powered using a MGTHAVCC, MGTHAVCCRX, MGTHAVCCPLL, and MGTHAVTT sequence. There are no sequencing requirement for these supplies with respect to the other FPGA supply voltages. For more detail see Table 27: *GTH Transceiver Power Supply Sequencing*. There are no sequencing requirements for the GTX transceivers power supplies.

Table 5 shows the minimum current, in addition to I_{CCQ}, that are required by Virtex-6 devices for proper power-on and configuration. If the current minimums shown in Table 4 and Table 5 are met, the device powers on after all three supplies have passed through their power-on reset threshold voltages. The FPGA must be configured after applying V_{CCINT}, V_{CCAUX}, and V_{CCO} for the appropriate configuration banks. Once initialized and configured, use the XPE tools to estimate current drain on these supplies.

Table 5: **Power-On Current for Virtex-6 Devices**

Device	$I_{CCINTMIN}$ Typ[1]	$I_{CCAUXMIN}$ Typ[1]	I_{CCOMIN} Typ[1]	Units
XC6VLX75T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 10	I_{CCOQ} + 30 mA per bank	mA
XC6VLX130T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 10	I_{CCOQ} + 30 mA per bank	mA
XC6VLX195T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VLX240T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VLX365T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VLX550T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VLX760	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VSX315T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VSX475T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 50	I_{CCOQ} + 30 mA per bank	mA
XC6VHX250T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VHX255T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VHX380T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XC6VHX565T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 40	I_{CCOQ} + 30 mA per bank	mA
XQ6VLX130T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 30 mA per bank	mA
XQ6VLX240T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 30 mA per bank	mA
XQ6VLX550T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 30 mA per bank	mA
XQ6VSX315T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 40 mA per bank	mA
XQ6VSX475T	See I_{CCINTQ} in Table 4	I_{CCAUXQ} + 100	I_{CCOQ} + 40 mA per bank	mA

Notes:
1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at http://www.xilinx.com/power) to calculate maximum power-on currents.

HT DC Specifications (HT_25)

Table 8: **HT DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OD}	Differential Output Voltage for XC devices	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	480	600	885	mV
	Differential Output Voltage for XQ devices		480	600	930	mV
ΔV_{OD}	Change in V_{OD} Magnitude		−15	–	15	mV
V_{OCM}	Output Common Mode Voltage	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	440	600	760	mV
ΔV_{OCM}	Change in V_{OCM} Magnitude		−15	–	15	mV
V_{ID}	Input Differential Voltage		200	600	1000	mV
ΔV_{ID}	Change in V_{ID} Magnitude		−15	–	15	mV
V_{ICM}	Input Common Mode Voltage		440	600	780	mV
ΔV_{ICM}	Change in V_{ICM} Magnitude		−15	–	15	mV

LVDS DC Specifications (LVDS_25)

Table 9: **LVDS DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	0.825	–	–	V
V_{ODIFF}	Differential Output Voltage (Q − $\overline{Q}$), Q = High ($\overline{Q}$ − Q), $\overline{Q}$ = High	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q − $\overline{Q}$), Q = High ($\overline{Q}$ − Q), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.3	1.2	2.2	V

Extended LVDS DC Specifications (LVDSEXT_25)

Table 10: **Extended LVDS DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	–	–	1.785	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	0.715	–	–	V
V_{ODIFF}	Differential Output Voltage (Q − $\overline{Q}$), Q = High ($\overline{Q}$ − Q), $\overline{Q}$ = High for XC devices	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	350	–	840	mV
	Differential Output Voltage (Q − $\overline{Q}$), Q = High ($\overline{Q}$ − Q), $\overline{Q}$ = High for XQ devices		350	–	850	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100 \ \Omega$ across Q and $\overline{Q}$ signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q − $\overline{Q}$), Q = High ($\overline{Q}$ − Q), $\overline{Q}$ = High	Common-mode input voltage = 1.25V	100	–	1000	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ±350 mV	0.3	1.2	2.2	V

GTH Transceiver Specifications

GTH Transceiver DC Characteristics

Table 25: **Absolute Maximum Ratings for GTH Transceivers**[1]

Symbol	Description	Min	Max	Units
MGTHAVCC	Analog supply voltage for the GTH transmitter, receiver, and common analog circuits	−0.5	1.125	V
MGTHAVCCRX	Analog supply voltage for the GTH receiver circuits and common analog circuits	−0.5	1.125	V
MGTHAVTT	Analog supply voltage for the GTH transmitter termination circuits	−0.5	1.32	V
MGTHAVCCPLL	Analog supply voltage for the GTH receiver and PLL circuits	−0.5	1.935	V
V_{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	−0.5	1.125	V
$V_{MGTREFCLK}$	Reference clock absolute input voltage	−0.5	1.935	V

Notes:

1. Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.

Table 26: **Recommended Operating Conditions for GTH Transceivers** [1][2]

Symbol	Description	Min	Typ	Max	Units
MGTHAVCC	Analog supply voltage for the GTH transmitter, receiver, and common analog circuits	1.075	1.1	1.125	V
MGTHAVCCRX	Analog supply voltage for the GTH receiver circuits and common analog circuits	1.075	1.1	1.125	V
MGTHAVTT	Analog supply voltage for the GTH transmitter termination circuits	1.140	1.2	1.26	V
MGTHAVCCPLL	Analog supply voltage for the GTH receiver and PLL circuit	1.710	1.8	1.89	V

Notes:

1. Each voltage listed requires the filter circuit described in UG371:*Virtex-6 FPGA GTH Transceivers User Guide*.
2. Voltages are specified for the temperature range of T_j = −40°C to +100°C.

Table 27: **GTH Transceiver Power Supply Sequencing** [1][2][3]

Symbol	Description	Min	Max	Units
$T_{HAVCC2HAVCCRX}$	Maximum time between powering MGTHAVCC to when MGTHAVCCRX must be powered.	0	5	ms
$T_{HAVCCRX2HAVCCPLL}$	Minimum time between powering MGTHAVCCRX to when MGTHAVCCPLL can be powered.	10	–	µs
$T_{HAVCCRX2HAVTT}$	Minimum time between powering MGTHAVCCRX to when MGTHAVTT can be powered.	10	–	µs

Notes:

1. MGTHAVCCRX must be powered simultaneously or within $T_{HAVCC2HAVCCRX}$ of MGTHAVCC, but it must not precede MGTHAVCC.
2. MGTHAVCC and MGTHAVCCRX must be powered before MGTHAVCCPLL and MGTHAVTT. This minimum time is defined by $T_{HAVCCRX2HAVCCPLL}$ and $T_{HAVCCRX2HAVTT}$.
3. At any time, the condition of MGTHAVCC being present and MGTHAVCCRX not being present should not occur for more than the maximum $T_{HAVCC2HAVCCRX}$.

GTH Transceiver Switching Characteristics

Consult [UG371](#):*Virtex-6 FPGA GTH Transceivers User Guide* for further information.

Table 32: **GTH Transceiver Maximum Data Rate and PLL Frequency Range**

Symbol	Description	Conditions	Speed Grade			Units
			-3	**-2**	**-1**	
F_{GTHMAX}	Maximum GTH transceiver data rate	PLL Output Divider = 1	11.182	11.182	10.32	Gb/s
		PLL Output Divider = 4	2.795	2.795	2.58	Gb/s
F_{GTHMIN}	Minimum GTH transceiver data rate[1]	PLL Output Divider = 1	9.92	9.92	9.92	Gb/s
		PLL Output Divider = 4	2.48	2.48	2.48	Gb/s
$F_{GPLLMAX}$	Maximum GTH PLL frequency		5.591	5.591	5.16	GHz
$F_{GPLLMIN}$	Minimum GTH PLL frequency		4.96	4.96	4.96	GHz

Notes:

1. Lower data rates can be achieved using FPGA logic based oversampling designs.

Table 33: **GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics**

Symbol	Description	Speed Grade			Units
		-3	**-2**	**-1**	
$F_{GTHDRPCLK}$	GTHDRPCLK maximum frequency	70	70	60	MHz

Table 34: **GTH Transceiver Reference Clock Switching Characteristics**

| Symbol	Description	Conditions	All Speed Grades			Units
			Min	**Typ**	**Max**	
F_{GCLK}	Reference clock frequency range	-1 speed grade	150	–	645	MHz
		-2 and -3 speed grades	150	–	700	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	CLK	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	2	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	20	µs
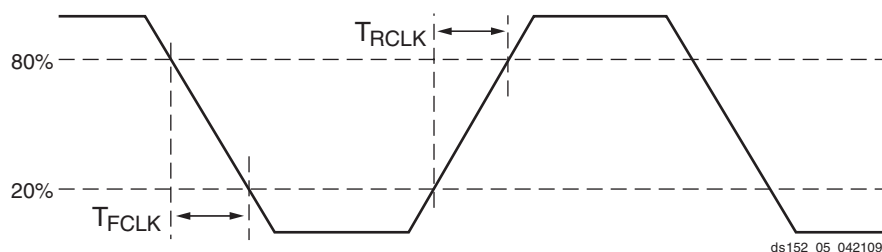
Figure 5: **Reference Clock Timing Parameters**

Table 37: **GTH Transceiver Receiver Switching Characteristics**

Symbol	Description		Min	Typ	Max	Units
R_{XRL}	Run length (CID)		8000	–	–	UI
$R_{XPPMTOL}$	Data/REFCLK PPM offset tolerance		–200	–	200	ppm
SJ Jitter Tolerance[1][2][3][4]						
$JT\_SJ_{11.18}$	Sinusoidal Jitter	11.18 Gb/s	0.3	–	–	UI
$JT\_SJ_{10.32}$	Sinusoidal Jitter	10.32 Gb/s	0.3	–	–	UI
$JT\_SJ_{9.95}$	Sinusoidal Jitter	9.95 Gb/s	0.3	–	–	UI
$JT\_SJ_{2.667}$	Sinusoidal Jitter	2.667 Gb/s	0.5	–	–	UI
$JT\_SJ_{2.48}$	Sinusoidal Jitter	2.48 Gb/s	0.5	–	–	UI

Notes:

1. These values are NOT intended for protocol specific compliance determinations.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. High-frequency jitter tolerance including 6 db of channel loss at a high frequency of the data rate divided by two.

Ethernet MAC Switching Characteristics

Consult UG368:*Virtex-6 FPGA Embedded Tri-mode Ethernet MAC User Guide* for further information.

Table 38: **Maximum Ethernet MAC Performance**

Symbol	Description	Conditions	Speed Grade				Units
			-3	**-2**	**-1**	**-1L**	
$F_{TEMACCLIENT}$	Client interface maximum frequency	10 Mb/s – 8-bit width	2.5[1]	2.5[1]	2.5[1]	2.5[1]	MHz
		100 Mb/s – 8-bit width	25[2]	25[2]	25[2]	25[2]	MHz
		1000 Mb/s – 8-bit width	125	125	125	125	MHz
		1000 Mb/s – 16-bit width	62.5	62.5	62.5	62.5	MHz
		2000 Mb/s – 16-bit width	125	125	125	N/A	MHz
		2500 Mb/s – 16-bit width	156.25	156.25	156.25	N/A	MHz
$F_{TEMACPHY}$	Physical interface maximum frequency	10 Mb/s – 4-bit width	2.5	2.5	2.5	2.5	MHz
		100 Mb/s – 4-bit width	25	25	25	25	MHz
		1000 Mb/s – 8-bit width	125	125	125	125	MHz
		2000 Mb/s – 8-bit width	250	250	250	N/A	MHz
		2500 Mb/s – 8-bit width	312.5	312.5	312.5	N/A	MHz

Notes:

1. When not using clock enable, the F_{MAX} is lowered to 1.25 MHz.
2. When not using clock enable, the F_{MAX} is lowered to 12.5 MHz.

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex-6 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the Switching Characteristics, page 26.

Table 41: **Interface Performances**

Description	Speed Grade			
	-3	**-2**	**-1**	**-1L**
Networking Applications				
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 10)	1.4 Gb/s	1.3 Gb/s	1.25 Gb/s	1.1 Gb/s
SDR LVDS receiver (SFI-4.1)[1]	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS receiver (SPI-4.2)[1]	1.4 Gb/s	1.3 Gb/s	1.1 Gb/s	0.9 Gb/s
Maximum Physical Interface (PHY) Rate for Memory Interfaces[2][3][4]				
DDR2	800 Mb/s	800 Mb/s	800 Mb/s	606 Mb/s
DDR3	1066 Mb/s	1066 Mb/s	800 Mb/s	800 Mb/s
QDR II + SRAM	400 MHz	350 MHz	300 MHz	–
RLDRAM II	500 MHz	400 MHz	350 MHz	–

Notes:

1. LVDS receivers are typically bounded with certain applications where specific DPA algorithms dominate deterministic performance.
2. Verified on Xilinx memory characterization platforms designed according to the guidelines in UG:*Virtex-6 FPGA Memory Interface Solutions User Guide*.
3. Consult DS186:*Virtex-6 FPGA Memory Interface Solutions Data Sheet* for performance and feature information on memory interface cores (controller plus PHY).
4. Memory Interface data rates have not been tested over the junction temperature operating range for military (M) temperature devices. Customers are responsible for specifying and testing their specific M temperature grade memory implementation.

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices *(Cont'd)*

I/O Standard	T_{IOPI} Speed Grade				T_{IOOP} Speed Grade				T_{IOTP} Speed Grade				Units
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
LVCMOS25, Fast, 24 mA	0.51	0.57	0.66	0.70	1.66	1.79	1.99	1.96	1.66	1.79	1.99	1.96	ns
LVCMOS18, Slow, 2 mA	0.55	0.61	0.71	0.73	4.21	4.47	4.87	4.30	4.21	4.47	4.87	4.30	ns
LVCMOS18, Slow, 4 mA	0.55	0.61	0.71	0.73	2.79	2.96	3.21	2.94	2.79	2.96	3.21	2.94	ns
LVCMOS18, Slow, 6 mA	0.55	0.61	0.71	0.73	2.30	2.43	2.64	2.47	2.30	2.43	2.64	2.47	ns
LVCMOS18, Slow, 8 mA	0.55	0.61	0.71	0.73	2.01	2.11	2.27	2.24	2.01	2.11	2.27	2.24	ns
LVCMOS18, Slow, 12 mA	0.55	0.61	0.71	0.73	1.88	1.99	2.15	2.10	1.88	1.99	2.15	2.10	ns
LVCMOS18, Slow, 16 mA	0.55	0.61	0.71	0.73	1.84	1.95	2.11	2.04	1.84	1.95	2.11	2.04	ns
LVCMOS18, Fast, 2 mA	0.55	0.61	0.71	0.73	4.00	4.23	4.57	4.08	4.00	4.23	4.57	4.08	ns
LVCMOS18, Fast, 4 mA	0.55	0.61	0.71	0.73	2.62	2.76	2.97	2.74	2.62	2.76	2.97	2.74	ns
LVCMOS18, Fast, 6 mA	0.55	0.61	0.71	0.73	2.15	2.28	2.46	2.32	2.15	2.28	2.46	2.32	ns
LVCMOS18, Fast, 8 mA	0.55	0.61	0.71	0.73	1.90	1.99	2.13	2.14	1.90	1.99	2.13	2.14	ns
LVCMOS18, Fast, 12 mA	0.55	0.61	0.71	0.73	1.69	1.80	1.97	1.88	1.69	1.80	1.97	1.88	ns
LVCMOS18, Fast, 16 mA	0.55	0.61	0.71	0.73	1.63	1.74	1.91	1.88	1.63	1.74	1.91	1.88	ns
LVCMOS15, Slow, 2 mA	0.64	0.73	0.85	0.85	3.43	3.77	4.29	3.91	3.43	3.77	4.29	3.91	ns
LVCMOS15, Slow, 4 mA	0.64	0.73	0.85	0.85	2.58	2.79	3.10	2.93	2.58	2.79	3.10	2.93	ns
LVCMOS15, Slow, 6 mA	0.64	0.73	0.85	0.85	2.08	2.32	2.68	2.50	2.08	2.32	2.68	2.50	ns
LVCMOS15, Slow, 8 mA	0.64	0.73	0.85	0.85	1.81	1.98	2.23	2.24	1.81	1.98	2.23	2.24	ns
LVCMOS15, Slow, 12 mA	0.64	0.73	0.85	0.85	1.76	1.91	2.13	2.07	1.76	1.91	2.13	2.07	ns
LVCMOS15, Slow, 16 mA	0.64	0.73	0.85	0.85	1.69	1.83	2.04	1.98	1.69	1.83	2.04	1.98	ns
LVCMOS15, Fast, 2 mA	0.64	0.73	0.85	0.85	3.44	3.77	4.28	3.91	3.44	3.77	4.28	3.91	ns
LVCMOS15, Fast, 4 mA	0.64	0.73	0.85	0.85	2.37	2.53	2.78	2.66	2.37	2.53	2.78	2.66	ns
LVCMOS15, Fast, 6 mA	0.64	0.73	0.85	0.85	1.80	2.05	2.42	2.16	1.80	2.05	2.42	2.16	ns
LVCMOS15, Fast, 8 mA	0.64	0.73	0.85	0.85	1.76	1.90	2.11	2.04	1.76	1.90	2.11	2.04	ns
LVCMOS15, Fast, 12 mA	0.64	0.73	0.85	0.85	1.64	1.77	1.97	1.90	1.64	1.77	1.97	1.90	ns
LVCMOS15, Fast, 16 mA	0.64	0.73	0.85	0.85	1.62	1.76	1.96	1.92	1.62	1.76	1.96	1.92	ns
LVCMOS12, Slow, 2 mA	0.72	0.81	0.93	0.95	3.14	3.39	3.75	3.54	3.14	3.39	3.75	3.54	ns
LVCMOS12, Slow, 4 mA	0.72	0.81	0.93	0.95	2.43	2.63	2.93	2.79	2.43	2.63	2.93	2.79	ns
LVCMOS12, Slow, 6 mA	0.72	0.81	0.93	0.95	1.92	2.11	2.41	2.26	1.92	2.11	2.41	2.26	ns
LVCMOS12, Slow, 8 mA	0.72	0.81	0.93	0.95	1.87	2.02	2.25	2.17	1.87	2.02	2.25	2.17	ns
LVCMOS12, Fast, 2 mA	0.72	0.81	0.93	0.95	2.71	2.98	3.39	3.11	2.71	2.98	3.39	3.11	ns
LVCMOS12, Fast, 4 mA	0.72	0.81	0.93	0.95	1.93	2.16	2.51	2.31	1.93	2.16	2.51	2.31	ns
LVCMOS12, Fast, 6 mA	0.72	0.81	0.93	0.95	1.75	1.89	2.11	2.05	1.75	1.89	2.11	2.05	ns
LVCMOS12, Fast, 8 mA	0.72	0.81	0.93	0.95	1.69	1.82	2.02	1.98	1.69	1.82	2.02	1.98	ns
LVDCI_25	0.51	0.57	0.66	0.70	2.05	2.14	2.26	2.26	2.05	2.14	2.26	2.26	ns
LVDCI_18	0.55	0.61	0.71	0.73	2.07	2.23	2.47	2.38	2.07	2.23	2.47	2.38	ns
LVDCI_15	0.64	0.73	0.85	0.85	1.85	2.01	2.24	2.18	1.85	2.01	2.24	2.18	ns

Table 45: **IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices** *(Cont'd)*

I/O Standard	T_{IOPI} Speed Grade			T_{IOOP} Speed Grade			T_{IOTP} Speed Grade			Units
	-2	**-1**	**-1L**	**-2**	**-1**	**-1L**	**-2**	**-1**	**-1L**	
DIFF_SSTL18_II	0.94	1.09	1.08	1.50	2.27	1.66	1.50	2.27	1.66	ns
DIFF_SSTL18_II_DCI	0.94	1.09	1.08	1.47	2.20	1.62	1.47	2.20	1.62	ns
DIFF_SSTL18_II_T_DCI	0.94	1.09	1.08	1.51	2.30	1.65	1.51	2.30	1.65	ns
DIFF_SSTL15	0.91	1.06	1.06	1.54	2.25	1.69	1.54	2.25	1.69	ns
DIFF_SSTL15_DCI	0.91	1.06	1.06	1.52	2.25	1.66	1.52	2.25	1.66	ns
DIFF_SSTL15_T_DCI	0.91	1.06	1.06	1.52	2.25	1.66	1.52	2.25	1.66	ns

Table 46: **IOB 3-state ON Output Switching Characteristics (T_{IOTPHZ})**

Symbol	Description	Speed Grade				Units
		-3	**-2**	**-1**	**-1L**	
T_{IOTPHZ}	T input to Pad high-impedance	0.86	0.92	0.99	0.99	ns

I/O Standard Adjustment Measurement Methodology

Input Delay Measurements

Table 47 shows the test setup parameters used for measuring input delay.

Table 47: **Input Delay Measurement Methodology**

Description	I/O Standard Attribute	V_L[1][2]	V_H[1][2]	V_{MEAS} [1][4][5]	V_{REF} [1][3][5]
LVCMOS, 2.5V	LVCMOS25	0	2.5	1.25	–
LVCMOS, 1.8V	LVCMOS18	0	1.8	0.9	–
LVCMOS, 1.5V	LVCMOS15	0	1.5	0.75	–
HSTL (High-Speed Transceiver Logic), Class I & II	HSTL_I, HSTL_II	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.75
HSTL, Class III	HSTL_III	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
HSTL, Class I & II, 1.8V	HSTL_I_18, HSTL_II_18	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
HSTL, Class III 1.8V	HSTL_III_18	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	1.08
SSTL (Stub Terminated Transceiver Logic), Class I & II, 3.3V	SSTL3_I, SSTL3_II	$V_{REF} - 1.00$	$V_{REF} + 1.00$	V_{REF}	1.5
SSTL, Class I & II, 2.5V	SSTL2_I, SSTL2_II	$V_{REF} - 0.75$	$V_{REF} + 0.75$	V_{REF}	1.25
SSTL, Class I & II, 1.8V	SSTL18_I, SSTL18_II	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	$1.2 - 0.125$	$1.2 + 0.125$	0[6]	–
LVDSEXT (LVDS Extended Mode), 2.5V	LVDSEXT_25	$1.2 - 0.125$	$1.2 + 0.125$	0[6]	–
HT (HyperTransport), 2.5V	LDT_25	$0.6 - 0.125$	$0.6 + 0.125$	0[6]	–

Notes:

1. The input delay measurement methodology parameters for LVDCI are the same for LVCMOS standards of the same voltage. Input delay measurement methodology parameters for HSLVDCI are the same as for HSTL_II standards of the same voltage. Parameters for all other DCI standards are the same for the corresponding non-DCI standards.
2. Input waveform switches between V_L and V_H.
3. Measurements are made at typical, minimum, and maximum V_{REF} values. Reported delays reflect worst case of these measurements. V_{REF} values listed are typical.
4. Input voltage level from which measurement starts.
5. This is an input voltage reference that bears no relation to the V_{REF} / V_{MEAS} parameters found in IBIS models and/or noted in Figure 6.
6. The value given is the differential input voltage.

Table 48: **Output Delay Measurement Methodology** *(Cont'd)*

Description	I/O Standard Attribute	R_{REF} (Ω)	C_{REF}[1] (pF)	V_{MEAS} (V)	V_{REF} (V)
HT (HyperTransport), 2.5V	LDT_25	100	0	0[2]	0.6
LVPECL (Low-Voltage Positive Emitter-Coupled Logic), 2.5V	LVPECL_25	100	0	0[2]	0
LVDCI/HSLVDCI, 2.5V	LVDCI_25, HSLVDCI_25	1M	0	1.25	0
LVDCI/HSLVDCI, 1.8V	LVDCI_18, HSLVDCI_18	1M	0	0.9	0
LVDCI/HSLVDCI, 1.5V	LVDCI_15, HSLVDCI_15	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I & II, with DCI	HSTL_I_DCI, HSTL_II_DCI	50	0	V_{REF}	0.75
HSTL, Class III, with DCI	HSTL_III_DCI	50	0	0.9	1.5
HSTL, Class I & II, 1.8V, with DCI	HSTL_I_DCI_18, HSTL_II_DCI_18	50	0	V_{REF}	0.9
HSTL, Class III, 1.8V, with DCI	HSTL_III_DCI_18	50	0	1.1	1.8
SSTL (Stub Series Termi.Logic), Class I & II, 1.8V, with DCI	SSTL18_I_DCI, SSTL18_II_DCI	50	0	V_{REF}	0.9
SSTL, Class I & II, 2.5V, with DCI	SSTL2_I_DCI, SSTL2_II_DCI	50	0	V_{REF}	1.25

Notes:

1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

Input/Output Logic Switching Characteristics

Table 49: **ILOGIC Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	**-2**	**-1**	**-1L**	
Setup/Hold						
T_{ICE1CK}/T_{ICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.21/ 0.03	0.25/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T_{ISRCK}/T_{ICKSR}	SR pin Setup/Hold with respect to CLK	0.66/ −0.08	0.78/ −0.08	0.96/ −0.08	1.09/ −0.11	ns
T_{IDOCK}/T_{IOCKD}	D pin Setup/Hold with respect to CLK without Delay	0.07/ 0.41	0.08/ 0.46	0.10/ 0.54	0.11/ 0.64	ns
T_{IDOCKD}/T_{IOCKDD}	DDLY pin Setup/Hold with respect to CLK (using IODELAY)	0.10/ 0.32	0.12/ 0.36	0.14/ 0.42	0.16/ 0.50	ns
Combinatorial						
T_{IDI}	D pin to O pin propagation delay, no Delay	0.15	0.17	0.20	0.23	ns
T_{IDID}	DDLY pin to O pin propagation delay (using IODELAY)	0.19	0.22	0.25	0.28	ns
Sequential Delays						
T_{IDLO}	D pin to Q1 pin using flip-flop as a latch without Delay	0.48	0.54	0.64	0.73	ns
T_{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY)	0.52	0.58	0.68	0.78	ns
T_{ICKQ}	CLK to Q outputs	0.54	0.61	0.70	0.93	ns
T_{RQ_ILOGIC}	SR pin to OQ/TQ out	0.85	0.97	1.15	1.32	ns
T_{GSRQ_ILOGIC}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	ns
Set/Reset						
T_{RPW_ILOGIC}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.30	ns, Min

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 55: **CLB Distributed RAM Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T$_{SHCKO}$	Clock to A – B outputs	0.92	1.10	1.36	1.49	ns, Max
T$_{SHCKO\_1}$	Clock to AMUX – BMUX outputs	1.19	1.40	1.71	1.87	ns, Max
Setup and Hold Times Before/After Clock CLK						
T$_{DS}$/T$_{DH}$	A – D inputs to CLK	0.62/0.18	0.72/0.20	0.88/0.22	0.98/0.23	ns, Min
T$_{AS}$/T$_{AH}$	Address An inputs to clock	0.19/0.52	0.22/0.59	0.27/0.66	0.30/0.75	ns, Min
T$_{WS}$/T$_{WH}$	WE input to clock	0.27/0.00	0.32/0.00	0.40/0.00	0.47/–0.03	ns, Min
T$_{CECK}$/T$_{CKCE}$	CE input to CLK	0.28/–0.01	0.34/–0.01	0.41/–0.01	0.48/–0.05	ns, Min
Clock CLK						
T$_{MPW}$	Minimum pulse width	0.70	0.82	1.00	1.04	ns, Min
T$_{MCP}$	Minimum clock period	1.40	1.64	2.00	2.08	ns, Min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.
2. T$_{SHCKO}$ also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 56: **CLB Shift Register Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T$_{REG}$	Clock to A – D outputs	1.11	1.30	1.58	1.74	ns, Max
T$_{REG\_MUX}$	Clock to AMUX – DMUX output	1.37	1.60	1.93	2.12	ns, Max
T$_{REG\_M31}$	Clock to DMUX output via M31 output	1.08	1.27	1.55	1.74	ns, Max
Setup and Hold Times Before/After Clock CLK						
T$_{WS}$/T$_{WH}$	WE input	0.05/0.00	0.07/0.00	0.09/0.00	0.11/0.03	ns, Min
T$_{CECK}$/T$_{CKCE}$	CE input to CLK	0.06/–0.01	0.08/–0.01	0.10/–0.01	0.12/0.02	ns, Min
T$_{DS}$/T$_{DH}$	A – D inputs to CLK	0.64/0.18	0.76/0.21	0.94/0.24	1.07/0.23	ns, Min
Clock CLK						
T$_{MPW}$	Minimum pulse width	0.60	0.70	0.85	0.89	ns, Min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Table 59: **Configuration Switching Characteristics** *(Cont'd)*

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T_{SMCKBY}	CCLK to BUSY out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to BUSY out in readback at 1.8V	6	6	6	7	ns, Max
F_{SMCCK}	Maximum Frequency with respect to nominal CCLK	100	100	100	70	MHz, Max
F_{RBCCK}	Maximum Readback Frequency with respect to nominal CCLK	100	100	100	60	MHz, Max
$F_{MCCKTOL}$	Frequency tolerance, master mode with respect to nominal CCLK	55	55	55	60	%
Boundary-Scan Port Timing Specifications						
T_{TAPTCK}/T_{TCKTAP}	TMS and TDI Setup time before TCK/ Hold time after TCK	3.0/2.0	3.0/2.0	3.0/2.0	4.0/2.0	ns, Min
T_{TCKTDO}	TCK falling edge to TDO output valid at 2.5V	6	6	6	7	ns, Max
	TCK falling edge to TDO output valid at 1.8V	6	6	6	7	ns, Max
F_{TCK}	Maximum configuration TCK clock frequency	66	66	66	33	MHz, Max
F_{TCKB_MIN}	Minimum boundary-scan TCK clock frequency when using IEEE Std 1149.6 (AC-JTAG). Minimum operating temperature for IEEE Std 1149.6 is 0°C.	15	15	15	15	MHz, Min
F_{TCKB}	Maximum boundary-scan TCK clock frequency	66	66	66	33	MHz, Max
BPI Master Flash Mode Programming Switching						
T_{BPICCO}[2]	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 2.5V	6	6	6	7	ns
	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 1.8V	6	6	6	7	ns
T_{BPIDCC}/T_{BPICCD}	Setup/Hold on D[15:0] data input pins	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns
$T_{INITADDR}$	Minimum period of initial ADDR[25:0] address cycles	3	3	3	3	CCLK cycles
SPI Master Flash Mode Programming Switching						
T_{SPIDCC}/$T_{SPIDCCD}$	DIN Setup/Hold before/after the rising CCLK edge	3.0/0.0	3.0/0.0	3.0/0.0	3.5/0.0	ns
T_{SPICCM}	MOSI clock to out at 2.5V	6	6	6	7	ns
	MOSI clock to out at 1.8V	6	6	6	7	ns
$T_{SPICCFC}$	FCS_B clock to out at 2.5V	6	6	6	7	ns
	FCS_B clock to out at 1.8V	6	6	6	7	ns
T_{FSINIT}/$T_{FSINITH}$	FS[2:0] to INIT_B rising edge Setup and Hold	2	2	2	2	µs
CCLK Output (Master Modes)						
T_{MCCKL}	Master CCLK clock Low time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
T_{MCCKH}	Master CCLK clock High time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
CCLK Input (Slave Modes)						
T_{SCCKL}	Slave CCLK clock minimum Low time	2.5	2.5	2.5	2.5	ns, Min
T_{SCCKH}	Slave CCLK clock minimum High time	2.5	2.5	2.5	2.5	ns, Min
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
F_{DCK}	Maximum frequency for DCLK	200	200	200	200	MHz
$T_{MMCMDCK\_DADDR}$/$T_{MMCMCKD\_DADDR}$	DADDR Setup/Hold	1.25/0.00	1.40/0.00	1.63/0.00	1.64/0.00	ns

Virtex-6 Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 68. Values are expressed in nanoseconds unless otherwise noted.

Table 68: **Global Clock Input Setup and Hold Without MMCM**

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.[1]							
T_{PSFD}/ T_{PHFD}	Full Delay (Legacy Delay or Default Delay) Global Clock Input and IFF[2] without MMCM	XC6VLX75T	1.33/ 0.03	1.44/ 0.03	1.75/ 0.03	2.18/ −0.22	ns
		XC6VLX130T	1.31/ −0.08	1.54/ −0.08	1.88/ −0.08	2.31/ −0.12	ns
		XC6VLX195T	1.36/ −0.11	1.60/ −0.11	1.97/ −0.11	2.40/ −0.25	ns
		XC6VLX240T	1.36/ −0.11	1.60/ −0.11	1.97/ −0.11	2.40/ −0.25	ns
		XC6VLX365T	1.79/ −0.28	1.87/ −0.28	2.17/ −0.28	2.48/ −0.24	ns
		XC6VLX550T	N/A	2.22/ −0.12	2.36/ −0.12	2.77/ −0.26	ns
		XC6VLX760	N/A	2.19/ −0.24	2.35/ −0.24	2.71/ −0.21	ns
		XC6VSX315T	1.75/ −0.09	1.85/ −0.09	2.06/ −0.09	2.47/ −0.24	ns
		XC6VSX475T	N/A	2.14/ −0.14	2.31/ −0.14	2.71/ −0.30	ns
		XC6VHX250T	1.93/ −0.22	2.04/ −0.22	2.25/ −0.22	N/A	ns
		XC6VHX255T	1.81/ −0.33	2.11/ −0.33	2.56/ −0.33	N/A	ns
		XC6VHX380T	1.93/ −0.11	2.04/ −0.11	2.25/ −0.11	N/A	ns
		XC6VHX565T	N/A	2.20/ −0.12	2.39/ −0.12	N/A	ns
		XQ6VLX130T	N/A	1.54/ −0.08	1.88/ −0.08	2.31/ −0.12	ns
		XQ6VLX240T	N/A	1.60/ −0.11	1.97/ −0.11	2.40/ −0.25	ns
		XQ6VLX550T	N/A	N/A	2.36/ −0.12	2.77/ −0.26	ns
		XQ6VSX315T	N/A	1.85/ −0.09	2.06/ −0.09	2.47/ −0.24	ns
		XQ6VSX475T	N/A	N/A	2.31/ −0.14	2.71/ −0.30	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Table 69: **Global Clock Input Setup and Hold With MMCM**

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.[1]							
T_{PSMMCMGC}/ T_{PHMMCMGC}	No Delay Global Clock Input and IFF[2] with MMCM	XC6VLX75T	1.45/ –0.18	1.57/ –0.18	1.72/ –0.18	1.78/ –0.08	ns
		XC6VLX130T	1.53/ –0.18	1.65/ –0.18	1.81/ –0.18	1.87/ –0.07	ns
		XC6VLX195T	1.54/ –0.17	1.66/ –0.17	1.82/ –0.17	1.87/ –0.08	ns
		XC6VLX240T	1.54/ –0.17	1.66/ –0.17	1.82/ –0.17	1.87/ –0.08	ns
		XC6VLX365T	1.55/ –0.18	1.67/ –0.18	1.83/ –0.18	1.87/ –0.07	ns
		XC6VLX550T	N/A	1.84/ –0.17	2.02/ –0.17	2.06/ –0.06	ns
		XC6VLX760	N/A	2.26/ –0.13	2.49/ –0.13	2.06/ –0.03	ns
		XC6VSX315T	1.56/ –0.18	1.68/ –0.18	1.84/ –0.18	1.89/ –0.08	ns
		XC6VSX475T	N/A	1.85/ –0.23	2.03/ –0.23	2.07/ –0.13	ns
		XC6VHX250T	1.52/ –0.17	1.64/ –0.17	1.80/ –0.17	N/A	ns
		XC6VHX255T	1.52/ –0.12	1.64/ –0.12	1.85/ –0.12	N/A	ns
		XC6VHX380T	1.68/ –0.16	1.81/ –0.16	1.99/ –0.16	N/A	ns
		XC6VHX565T	N/A	1.81/ –0.01	1.99/ –0.01	N/A	ns
		XQ6VLX130T	N/A	1.65/ –0.18	1.81/ –0.18	1.87/ –0.07	ns
		XQ6VLX240T	N/A	1.66/ –0.17	1.82/ –0.17	1.87/ –0.08	ns
		XQ6VLX550T	N/A	N/A	2.02/ –0.17	2.06/ –0.06	ns
		XQ6VSX315T	N/A	1.68/ –0.18	1.84/ –0.18	1.89/ –0.08	ns
		XQ6VSX475T	N/A	N/A	2.03/ –0.23	2.07/ –0.13	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Clock Switching Characteristics

The parameters in this section provide the necessary values for calculating timing budgets for Virtex-6 FPGA clock transmitter and receiver data-valid windows.

Table 71: **Duty Cycle Distortion and Clock-Tree Skew**

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{DCD_CLK}	Global Clock Tree Duty Cycle Distortion[1]	All	0.12	0.12	0.12	0.12	ns
T_{CKSKEW}	Global Clock Tree Skew[2]	XC6VLX75T	0.15	0.16	0.18	0.17	ns
		XC6VLX130T	0.25	0.26	0.29	0.28	ns
		XC6VLX195T	0.26	0.27	0.31	0.30	ns
		XC6VLX240T	0.26	0.27	0.31	0.30	ns
		XC6VLX365T	0.28	0.29	0.31	0.31	ns
		XC6VLX550T	N/A	0.50	0.54	0.54	ns
		XC6VLX760	N/A	0.51	0.56	0.56	ns
		XC6VSX315T	0.27	0.28	0.32	0.30	ns
		XC6VSX475T	N/A	0.39	0.44	0.42	ns
		XC6VHX250T	0.25	0.26	0.29	N/A	ns
		XC6VHX255T	0.35	0.37	0.41	N/A	ns
		XC6VHX380T	0.45	0.47	0.52	N/A	ns
		XC6VHX565T	N/A	0.46	0.51	N/A	ns
		XQ6VLX130T	N/A	0.26	0.29	0.28	ns
		XQ6VLX240T	N/A	0.27	0.31	0.30	ns
		XQ6VLX550T	N/A	N/A	0.54	0.54	ns
		XQ6VSX315T	N/A	0.28	0.32	0.30	ns
		XQ6VSX475T	N/A	N/A	0.44	0.42	ns
T_{DCD_BUFIO}	I/O clock tree duty cycle distortion	All	0.08	0.08	0.08	0.08	ns
$T_{BUFIOSKEW}$	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.02	ns
$T_{BUFIOSKEW2}$	I/O clock tree skew across three clock regions	All	0.10	0.12	0.23	0.12	ns
T_{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.15	0.15	0.15	0.15	ns

Notes:

1. These parameters represent the worst-case duty cycle distortion observable at the pins of the device using LVDS output buffers. For cases where other I/O standards are used, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.

2. The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

Table 73: **Sample Window**

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{SAMP}	Sampling Error at Receiver Pins[1]	All	510	560	610	670	ps
T_{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO[2]	All	300	350	400	440	ps

Notes:

1. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
   - CLK0 MMCM jitter
   - MMCM accuracy (phase offset)
   - MMCM phase shift resolution
   These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IODELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 74: **Pin-to-Pin Setup/Hold and Clock-to-Out**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO						
T_{PSCS}/T_{PHCS}	Setup/Hold of I/O clock	–0.28/1.09	–0.28/1.16	–0.28/1.33	–0.18/1.79	ns
Pin-to-Pin Clock-to-Out Using BUFIO						
$T_{ICKOFCS}$	Clock-to-Out of I/O clock	4.22	4.59	5.22	5.63	ns

Revision History

The following table shows the revision history for this document:

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
07/16/09	1.1	Revised the maximum V_{CCAUX} and V_{IN} numbers in Table 2, page 2. Removed empty column from Table 3, page 3. Revised specifications on Table 20, page 13. Updated Table 38, page 22 and added notes 1 and 2. Revised T_{DLYCCO_RDY}, $T_{IDELAYCTRL\_RPW}$, and $T_{IDELAYPAT\_JIT}$ in Table 53, page 41. Updated Table 58, page 46 to more closely match the DSP48E1 speed specifications. Updated T_{TAPTCK}/T_{TCKTAP} in Table 59, page 49. Updated XC6VLX130T parameters in Table 68 through Table 70, page 59.
08/19/09	1.2	Added values for -1L voltages and speed grade in all pertinent tables. Added V_{FS} and notes to Table 1 and Table 2. Removed DV_{PPIN} from the example in Figure 2. Added networking applications to Table 41, page 25. Changed and added to the block RAM F_{MAX} section in Table 57, page 44 including removing Note 12. Changed F_{PFDMAX} values and corrected units for $T_{STATPHAOFFSET}$ and $T_{OUTDUTY}$ in Table 64, page 52. Updated Table 71, page 60.
09/16/09	2.0	Added Virtex-6 HXT devices to entire document including GTH Transceiver Specifications. Updated speed specifications as described in Switching Characteristics, includes changes in Table 51, Table 57, Table 58, and Table 66 through Table 70. Comprehensive changes to Table 14, Table 15, and Table 16. Added conditions to D_{VPPOUT} and revised description of T_{OSKEW} in Table 17. Removed V_{ISE} specification and note from Table 18. Added note 3 to Table 23. Updated note 3 in Table 24. Updated LVCMOS25 delays in Table 44. Updated specification for T_{IOTPHZ} in Table 46. Removed $T_{BUFHSKEW}$ from Table 71, page 60 and added values for $T_{BUFIOSKEW}$. Added values in Table 74.

Date	Version	Description of Revisions
01/18/10	2.1	Changed absolute maximum ratings for both V_{IN} and V_{TS} in Table 1. Added data to Table 3. Added data to Table 5. Updated SSTL15 in Table 7. Updated V_{OCM} and V_{OD} values in Table 8. Added eFUSE endurance Table 12. Added values to $V_{MGTREFCLK}$ and V_{IN} in Table 13, page 11. Added values and updated tables in the GTX Transceiver Specifications and GTH Transceiver Specifications sections. Added Table 27 and Figure 4. Revised parameters and values in Table 39. Updated Table 40, page 23. Added data to Table 41. Updated speed specification to v1.04 with appropriate changes to Table 42 and Table 43 including production release of the XC6VLX240T for -1 and -2 speed grades. Speed specification changes and numerous updates also made to Table 44, and Table 49 through Table 71. Added data to Table 73 and Table 74.
02/09/10	2.2	Revised description of C_{IN} in Table 3. Clarified values in Table 5. Fixed SDR LVDS unit error in Table 41.
04/12/10	2.3	Added note 3 and update value of n in Table 3. Clarified simultaneous power-down in Power-On Power Supply Requirements. Updated external reference junction temperatures in Table 40, Analog-to-Digital Specifications. Updated speed specification to v1.05 with appropriate changes to Table 42 and Table 43 including production release of the XC6VLX130T for -1 and -2 speed grades. Fixed note 4 in Table 48. Increased the -2 specification for $F_{IDELAYCTRL\_REF}$ and clarified units for $T_{IDELAYPAT\_JIT}$ in Table 53. Added note 1 to Table 62.
05/11/10	2.4	Updated F_{RXREC} in Table 22. Revised $F_{IDELAYCTRL\_REF}$ in Table 53. Removed $T_{RCKO\_PARITY\_ECC}$: Clock CLK to ECCPARITY in standard ECC mode row in Table 57. Added XC6VLX130T values to Table 72.
05/26/10	2.5	Added XC6VLX195T data to Table 5. Updated values in Table 22 including adding note 2 and note 3. Updated speed specification to v1.06 with appropriate changes to Table 42 and Table 43 including production release of the XC6VLX195T for -1 and -2 speed grades. Added XC6VLX195T values to Table 72.
07/16/10	2.6	Changed Table 42 and Table 43 to production status on the -3 speed grade XC6VLX130T, XC6VLX195T, and XC6VLX240T devices. Added XC6VHX250Tdata to Table 4 and Table 72. Added Note 6 to Table 64.
07/23/10	2.7	Changed Table 42 and Table 43 to production status on the XC6VLX75T, XC6VLX365T, XC6VLX550T, XC6VLX760, XC6VSX315T, and XC6VSX475T devices using ISE 12.2 software with speed specification v1.08. Updated $V_{CMOUTDC}$ equation to MGTAVTT – D_{VPPOUT}/4 in Table 17. Updated some -3, -2, -1 specifications in Table 65 through Table 72. Added and updated -1L specifications to Table 41 and for most switching characteristics tables.
07/30/10	2.8	Changed Table 42 and Table 43 to production status on the -1L speed grade for the XC6VLX130T, XC6VLX195T, XC6VLX240T, XC6VLX365T, and XC6VLX550T devices using ISE 12.2 software with current speed specifications. Also updated the speed specifications for XC6VLX75T, XC6VLX550T, and XC6VSX315T. Updated V_{CCINT} specifications for -1L speed grade industrial temperature range devices in Table 2.
09/20/10	2.9	In Table 32, changed $F_{GPLLMAX}$ specification in -3 column from 5.951 to 5.591. In Table 40, changed F_{MAX} for the DCLK from 250 MHz to 80 MHz.
10/18/10	2.10	The specification change in version 2.9, Table 40 is described in XCN10032, *Virtex-6 FPGA: GTX Transceiver User Guide, Family Data Sheet (SYSMON DCLK), and JTAG ID Changes* In this version (2.10), -1L(I) data is added to Table 4 and clarified in Note 2. Changed Table 42 and Table 43 to production status on the -1L speed grade XC6VLX75T, XC6VLX760, XC6VSX315T, and XC6VSX475T devices using ISE 12.3 software with current speed specifications. Revised the XC6VLX760 -1L speed specification for $T_{PHMMCMGC}$ in Table 69 and $T_{PHMMCMCC}$ in Table 70.
01/17/11	2.11	Changed in Table 42 and Table 43 to production status on the XC6VHX250T devices using ISE 12.4 software with current speed specifications. Added industrial temperature range (T_j) recommended specifications to Table 2; including specific ranges for the -2I XC6VSX475T, XC6VLX550T, XC6VLX760, and XC6VHX565Tdevices. Added note 3 to Table 36 and maximum total jitter values. Added note 4 to Table 37 and maximum sinusoidal jitter values. Added note 2 to Table 43. Revised F_{MAX} descriptions in Table 57 and added note 12. Added note 8 to F_{PFDMIN} in Table 64. The following revisions are due to specification changes as described in XCN11009, *Virtex-6 FPGA: Data Sheet, User Guides, and JTAG ID Updates*. In Table 59:*Configuration Switching Characteristics*, page 49, revised -1L specifications for T_{POR}, F_{MCCK}, $F_{MCCKTOL}$, $T_{SMCSCCK}$, T_{SMCCKW}, F_{RBCCK}, F_{TCK}, F_{TCKB}, T_{MCCKL}, and T_{MCCKH}. In Table 64: *MMCM Specification*, added bandwidth settings to F_{PFDMIN} and added note 1.

Date	Version	Description of Revisions
02/08/11	2.12	Removed note 1 from Table 4 as the larger devices (XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX565T) are now offered in -2I. Updated Table 4 and Table 5 with data for the XC6VHX380T in the FF(G)1154 package. In Table 41, updated -1L specification for DDR3. Added Note 1 to Table 42. Moved the XC6VHX380Tdevices in the FF(G)1154 package to production release in Table 43 using ISE 12.4 software with current speed specifications. Updated description for F_{INDUTY} in Table 64.
02/25/11	3.0	Designated the data sheet as Preliminary for all devices not already labeled production in Table 42. Changed the XC6VHX380T devices in all packages to production status in Table 42 and Table 43. Removed note 1 from Table 42. Added maximum specifications to Table 25. Updated $T_{HAVCC2HAVCCRX}$ in Table 27. Updated the typical values and notes in Table 28 and Table 29. Added values to Table 30 and Table 31. In Table 34, added values for T_{LOCK} and T_{PHASE}. Updated the values in Table 36 and added note 3. Updated Table 37 and added note 4.
03/21/11	3.1	Updated Table 2 including Note 7. In Table 4, added Note 3 and -2E, extended temperature range to the XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX380T devices, and added Note 5 for the XC6VHX565T. Updated Table 28 typical values. Updated the description for $F_{IDELAYCTRL\_REF}$ in Table 53. Updated F_{MCCK} in Table 59.
04/01/11	3.2	Added Tj values for C, E, and I temperature ranges to Table 2. Updated the I_{CCQ} values in Table 4. Updated F_{GCLK} in Table 34. Designated the data sheet as Production for all devices not already labeled production in Table 42. Changed the XC6VHX255T and XC6VHX565T devices in all packages to production status in Table 42 and Table 43. This included updates to the Virtex-6 Device Pin-to-Pin Output Parameter Guidelines and Virtex-6 Device Pin-to-Pin Input Parameter Guidelines for these devices. Production speed specifications for these devices are available using the speed specification v1.14 in the ISE 13.1 software update. Updated and added package skew values to Table 72; these values are correct with regards to previous production released speed specifications in software. Updated copyright page 1 and Notice of Disclaimer.
12/08/11	3.3	Production release of the Defense-grade XQ devices in Table 42 and Table 43 using ISE v13.3 v1.17 Patch for -2 and -1 speed specifications; and v1.10 for -1L speed specifications. Added the XQ6VLX130T, XQ6VLX240T, XQ6VLX550T, XQ6VSX315T, and XQ6VSX475T to the data sheet which included adding Table 45. Updated T_j in Table 2. In Table 40, updated T_j for most specifications and added Note 4. Added Note 4 to Table 41. Added -1(XQ) speed specification columns only to Table 50, Table 51, Table 52, and Table 58. Updated V_{OD} in Table 8, V_{OCM} in Table 9, and V_{OCM} and V_{DIFF} in Table 10. Updated the Power-On Power Supply Requirements section. In Table 27, updated maximum specification for $T_{HAVCC2HAVCCRX}$ and added Note 3. Updated Tj in Table 40. In Table 41, increased the DDR LVDS receiver (SPI-4.2) -1 speed grade performance value from 1.0 Gb/s to 1.1 Gb/s. In Table 60, updated the F_{MAX} to add a separate row for the LX760 device values. The speed specifications in the software tools have always matched these values for the LX760, the data sheet is now correct. Updated the notes for $T_{OUTJITTER}$ in Table 64.
01/12/12	3.4	Added the temperature range -2E to Note 5 in Table 4.

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